

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1680	PRIORITY SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		
				PRIORITY FILING DATE February 24, 2000	PRIORITY GROUP 2858	
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa		
VN	AB	4,754,555	7/5/88	Stillman		
VN	AC	5,475,317	12/12/95	Smith		
VN	AD	5,495,667	3/5/96	Farnworth et al.		
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AE	S/N: 09/052,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99; Original Application filed 3/27/98; Pending Claims;				
VN	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc., 1 page; 3/6/98				
VN	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98				
VN	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.				
VN	AI	Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.				
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.				
VN	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.				
VN	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98				
EXAMINER <i>Mark Nguyen</i>				DATE CONSIDERED <i>02/07/2002</i>		
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>						

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/825,664	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
VN	AA	5,378,311	1/3/95	Nagayama et al.				
	AB							
	AC							
	AD							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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	AL							
EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED <i>02/07/2002</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								